

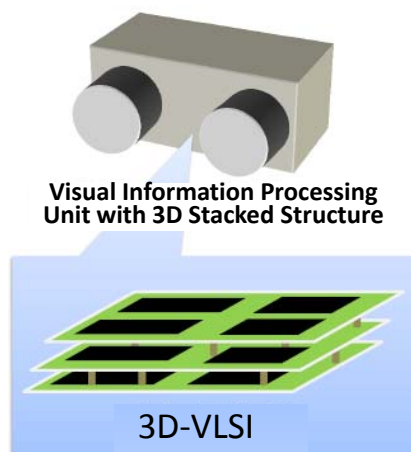
JST International Symposium on
Dependable VLSI Systems 2012

Development of 3D-VLSI System with Self-Test and Self-Repair Function

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1

Setting Target for High Performance Image Processing System to Guarantee Safety in Automobile Driving Assist



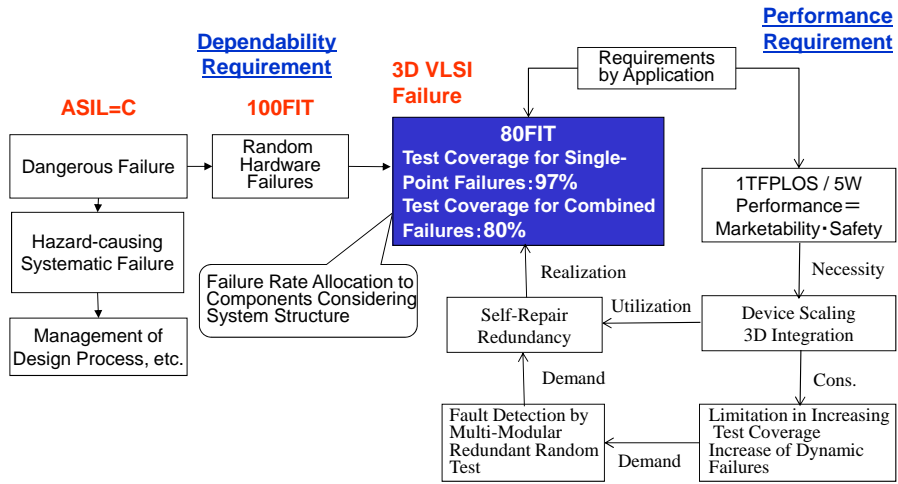
- Number of camera: 2
- Measuring distance: 0~100m
- Base line length: 12cm
- Focus length: 6.5cm
- Pixel resolution: SXGA
- Window size: 48 pixels x 31 lines
- Reconfiguration points: 30,000
- Matching accuracy: 1/20 Pixel
- Z Axis resolution
(Measuring distance accuracy):
80cm resolution at 50m ahead
3m resolution at 100m ahead
- Calculating ability : ~1TFLOPS

2

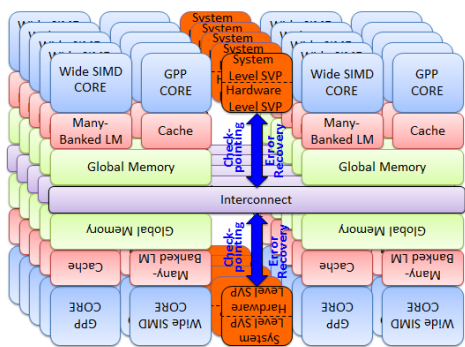
Application of 3D VLSI to Image Processing VLSI for Automobile

Relation between Requirements by Application and Various Technologies

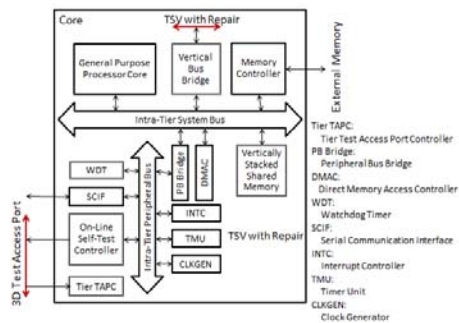
Target : ISO 26262 ASIL=C



Architecture of 3D-DVLSI System



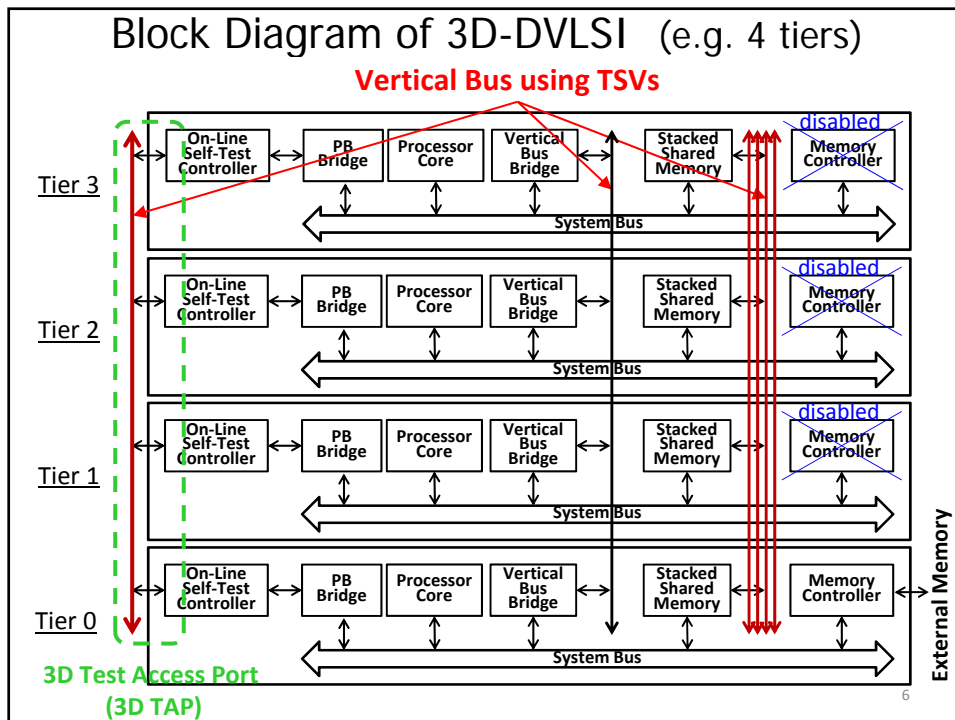
Configuration of 3D stacked multicore processor



Block diagram of a processor core

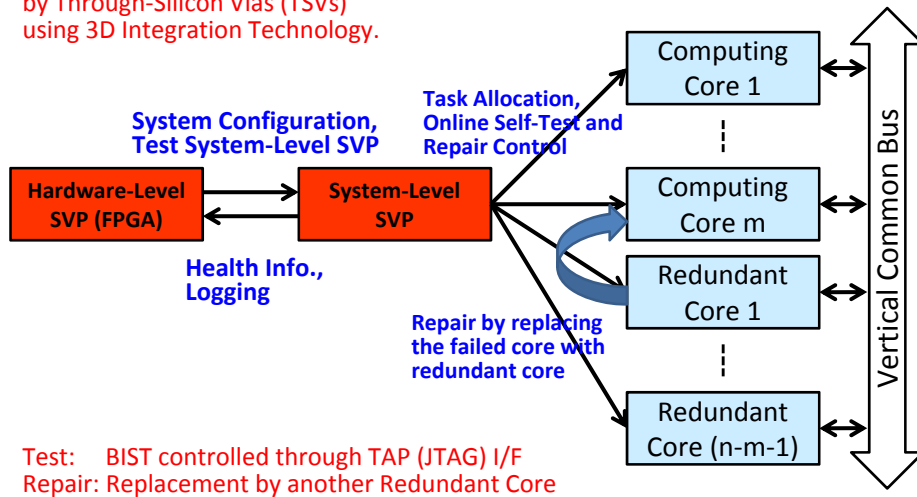
Purpose for Fabrication of Prototype 3D-Stacked Graphics Processor

- ▶ Evaluation of self-test control
 - ▶ BIST operation control
- ▶ Verification of design methodology for TSV circuits
 - ▶ DFT for TSV
 - ▶ Electrical conduction pass test for each TSV
 - ▶ TSV repair method
 - ▶ Arrangement of repair TSVs for a group of signal TSVs
 - ▶ Replacement of failure TSVs by repair TSVs which pass electrical conduction test.
- ▶ Integration of functional blocks by TSVs
 - ▶ Vertical buses/ Vertical bus bridges
 - ▶ Integration of 3D shared memory
 - ▶ Maintaining of consistency
 - Maintaining consistency by updating memory contents at appropriate intervals using memory-update vertical buses
 - Memory access control by prohibiting memory access for updating memory area with each line.
 - Providing vertical buses for memory updating to each page
 - ▶ No memory replacement function as in cache memory



Dependability Maintained by SVP

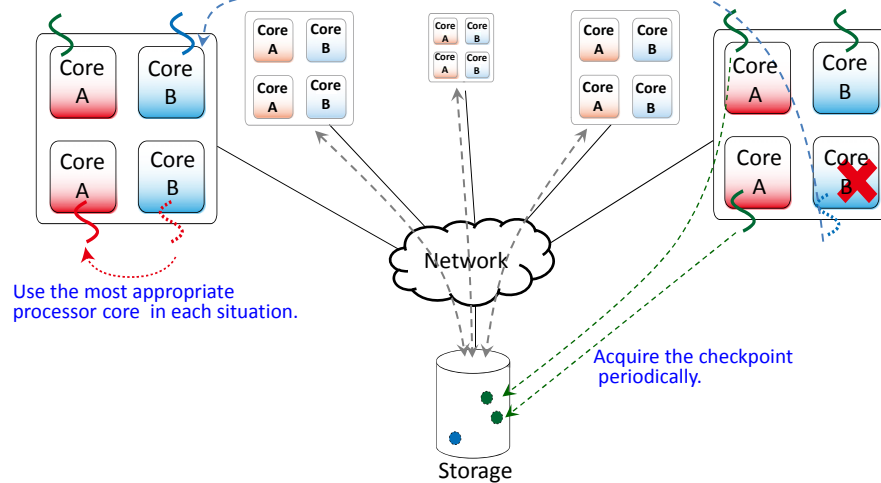
Vertically Stacked and Electrically Connected by Through-Silicon Vias (TSVs) using 3D Integration Technology.



7

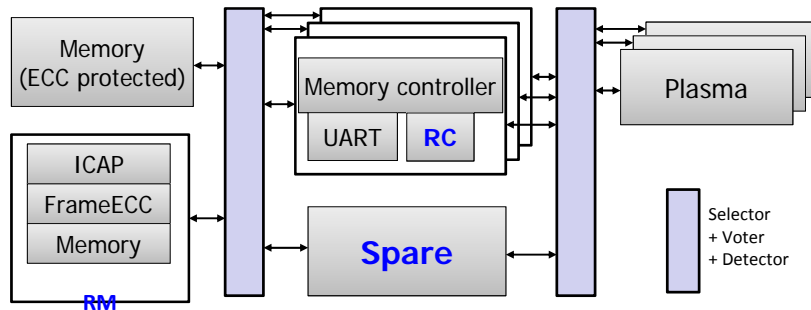
Check-Point and Restart Scheme for Heterogeneous Computing Platform

Restart a procedure at the checkpoint using functionable processor when failures occur.



8

Dependable HW-SVP



Implemented on : Xilinx Virtex-6 XC6VLX240T

- Triplicating processor core and peripheral modules
- Implementing RM, RC and Spare
 - RM and RC control recovery sequence
 - Spare is used for hard-error avoidance

RC : Recovery Controller

RM : Recovery Module

ICAP : Internal Configuration Access Port

9

Summary

- We proposed a new dependable architecture for 3D-VLSI in which a system supervisor processor (Sys-SVP) controls self-test and self-repair circuits and a hardware system supervisor processor (HW-SVP) controls Sys-SVP to maintain dependability.
- We established a self-repair scheme with soft-error recovery using dynamic reconfiguration and hard-error avoidance using partial reconfiguration to guarantee dependability of HW-SVP.
- We employed a checkpoint and restart scheme to migrate all function in a failure processor layer to another processor layer to maintain dependability and proposed a new algorithm to dynamically perform self-test and migration to maintain performance in 3D stacked graphics processor.
- We introduced a new 3D DfT (Design for Test) architecture with on-line self-test using Sys-SVP through 3D TAP (test access port) based on IEEE 1149.1. into 3D stacked graphics processor to maintain dependability.
- We introduced redundancy methods to guarantee the reliability of TSVs (Through Si Vias) in 3D-VLSI.
- We evaluate power efficiency of 3D-VLSI assuming the application to image processing for automobile of obstacle detection using stereo vision with POC (Phase-Only Correlation)-based correspondence matching.

10